

ABSTRACT

It is an object of the present invention to enable a strict and efficient inspection for a defect in a geometric pattern of a ferromagnetic thin-film layer of a master disk for magnetic recording media used in a device such as an AVHDD, in which initial information is recorded. Alignment marks 16 are formed in a plurality of positions on a circumference concentric with the recording section simultaneously with forming recording bands 14 constituting the information recording section on the master disk 10, the image of the recording bands 14 and the marks 16 on the master disk 10 is obtained, the image of recording section and non-defective product information is aligned based on the image of the marks 16, and then the images of the recording bands 14 are compared with the non-defective information to inspect the geometry pattern of the information recording section.